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PPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION N	
09/652,994	08/31/2000	Vishnu K. Agarwal	98-0616.01	4014	
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Please find below and/or attached an Office communication concerning this application or proceeding.



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APPLICATION NO.

FILING DATE FIRST NAMED INVENTOR / ATTORNEY DOCKET NO.

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PATENT IN REEXAMINATION

EXAMINER

ART UNIT PAPER

030504

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**Commissioner for Patents** 

The Information Disclosure Statements filed 05/30/03 and 06/27/03 have been considered by the Examiner.

Jan Genty

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Information disclosure statement					APPLICANT(S) Vishnu K. Agarwal						
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ATTY. DOCKET NO. APPLICATION NO. FORM PTO-1449 \* U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE (REV.7-80) 501082.02 (98-0616.01) 09/652,994 APPLICANT(S) INFORMATION DISCUSSURE STATEMENT Vishnu K. Agarwal GROUP ART UNIT FILING DATE August 31, 2000 2815 **U.S. PATENT DOCUMENTS** FILING DATE SUBCLASS NAME CLASS \*EXAMINER DATE MART IF APPROPRIATE 02/20/01 430 315 6,190,837 B1 Jung et al. ΑB AC AD ۸E ۸F AG ΑH Al FOREIGN PATENT DOCUMENTS CLASS SUBCLASS TRANSLATION COUNTRY DOCUMENT NUMBER DATE NO YES ΑX AL ٨M AN AO OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.) ΑP AQ AR DATE CONSIDERED **EXAMINER** \* EXAMINER: Initial/if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).

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